

**Notice of References Cited**

Application/Control No.

10/804,745

Applicant(s)/Patent Under

Reexamination

PERISHO ET AL

Examiner

TAN Q. NGUYEN

Art Unit

3661

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,467,283	11-1995	Butsuen et al.	701/301
*	B	US-5,627,756	05-1997	Fukada et al.	701/70
*	C	US-6,141,617	10-2000	Matsuda et al.	701/72
*	D	US-6,175,799	01-2001	Tsutsumi et al.	701/96
*	E	US-6,317,679	11-2001	Sielagoski et al.	701/96
*	F	US-6,753,804	06-2004	Miyahara, Shunji	342/70
*	G	US-6,763,904	07-2004	Winner et al.	180/167
*	H	US-7,051,827	05-2006	Cardinal et al.	180/174
*	I	US-2003/0201878	10-2003	Bai et al.	340/435
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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